

Notice of References Cited

Application/Control No.

10/592,959

Applicant(s)/Patent Under
Reexamination
TAKEZAWA, HIDEHARU

Examiner

Jacob Buchanan

Art Unit

1795

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0031710 A1	03-2002	Kezuka et al.	429/303
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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